

Search Notes**Application/Control No.**

10/685,738

Examiner

Kin-Chan Chen

Applicant(s)/Patent under Reexamination

KIM ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	706	5/2/2005	KCC
	710		
	712		
	714		
	723		
	724		
	745		
	756		
438	757	5/2/05	K-CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST key words search, USPAT, US- PGPUB, EPO, JPO, Derwent, IBM- TDB, inventor search.	5/2/2005	KCC